Search Notes					

•	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/817,594	SURNILLA ET AL.
	Examiner	Art Unit
	T 14 Amachiaht	2747

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Class	Subclass	Date	Examiner
123	90.11 90.15 90.16 90.17 198F 481	9/11/2006	TMA
ABOVE	UPPATED	2/13/2007	ma
ABOYE	UPDATED	2/13/2007 5/31/2007	TWA
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INT	INTERFERENCE SEARCHED				
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